

54LS/74LS670

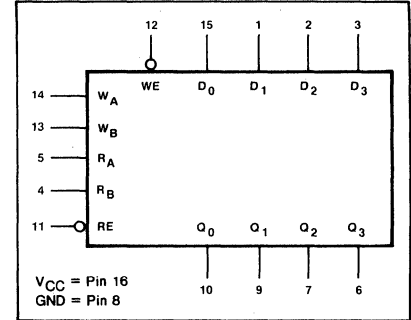
DESCRIPTION

The "670" is a 4-by-4 Register File with 3-State outputs organized as 4-words of 4-bits. Simultaneous read and write operation is allowed by separate read and write inputs, both address and enable. An almost unlimited number of devices can be stacked to increase the word capacity by tying the 3-state outputs together. Any number of these devices can be operated in parallel to generate an n-bit word.

FEATURES

- Simultaneous and independent Read and Write operations
- Expandable to almost any word size and bit length
- 3-State outputs
- See "170" for open collector version

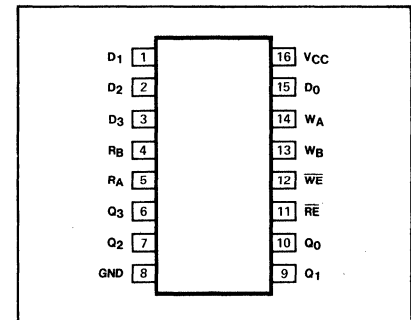
LOGIC SYMBOL



ORDERING CODE (See Section 9 for further Package and Ordering Information)

PACKAGES	COMMERCIAL RANGES	MILITARY RANGES
	$V_{CC}=5V \pm 5\%$ ; $T_A=0^\circ C$ to $+70^\circ C$	$V_{CC}=5V \pm 10\%$ ; $T_A=-55^\circ C$ to $+125^\circ C$
Plastic DIP	N74LS670N	
Ceramic DIP	N74LS670F	S54LS670F
Flatpak		S54LS670W

PIN CONFIGURATION



INPUT AND OUTPUT LOADING AND FAN-OUT TABLE (a)

PINS	DESCRIPTION		54/74	54S/74S	54LS/74LS
D <sub>0</sub> -D <sub>3</sub>	Data inputs	$I_{IH}$ ( $\mu A$ ) $I_{IL}$ (mA)			20 -0.4
W <sub>A</sub> , W <sub>B</sub>	Write address inputs	$I_{IH}$ ( $\mu A$ ) $I_{IL}$ (mA)			20 -0.4
$\overline{WE}$	Write Enable (active LOW) input	$I_{IH}$ ( $\mu A$ ) $I_{IL}$ (mA)			40 -0.8
R <sub>A</sub> , R <sub>B</sub>	Read address inputs	$I_{IH}$ ( $\mu A$ ) $I_{IL}$ (mA)			20 -0.4
$\overline{RE}$	Read Enable (active LOW) input	$I_{IH}$ ( $\mu A$ ) $I_{IL}$ (mA)			40 -0.8
Q <sub>0</sub> -Q <sub>3</sub>	Outputs	$I_{OH}$ (mA) $I_{OL}$ (mA)			-1/-2.6(a) 4/8(a)

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (d)

PARAMETER	TEST CONDITIONS	54/74		54S/74S		54LS/74LS		UNIT
		Min	Max	Min	Max	Min	Max	
V <sub>OH</sub> Output HIGH voltage	V <sub>CC</sub> = Min $I_{OH} = -1.0mA$ $I_{OH} = -2.6mA$					2.4		V
						2.4(e)		V
I <sub>CC</sub> Supply current	V <sub>CC</sub> = Max						50	mA

NOTES

- a. The slashed numbers indicate different parametric values for Military/Commercial temperature ranges respectively. e. This parameter for Commercial range only.  
 d. For family dc characteristics, see inside front cover for 54/74 and 54H/74H, and see inside back cover for 54S/74S and 54LS/74LS specifications.

**FUNCTIONAL DESCRIPTION**

The "670" is a 16-bit 3-State Register File organized as 4-words of 4-bits each. Separate read and write address and enable inputs are available permitting simultaneous writing into one word location and reading from another location. The 4-bit word to be stored is presented to four data inputs. The Write Address inputs ( $W_A$  &  $W_B$ ) determine the location of the stored word. When the Write Enable ( $\overline{WE}$ ) input is LOW, the data is entered into the addressed location. The addressed location remains transparent to the data while the  $\overline{WE}$  is LOW. Data supplied at the inputs will be read out in true (non-inverting) form from the 3-state outputs. Data and Write Address inputs are inhibited when  $\overline{WE}$  is HIGH.

Direct acquisition of data stored in any of the four registers is made possible by individual Read Address inputs ( $R_A$  &  $R_B$ ). The addressed word appears at the four outputs when the Read Enable ( $\overline{RE}$ ) is LOW. Data outputs are in the high impedance "off" state when the Read Enable input is HIGH. This permits outputs to be tied together to increase the word capacity to very large numbers.

Up to 128 devices can be stacked to increase the word size to 512 locations by tying the 3-state outputs together. Since the limiting factor for expansion is the output HIGH current, further stacking is possible by tying pull up resistors to the outputs to increase the  $I_{OH}$  current available. Design of the Read Enable signals for the stacked devices must ensure that there is no overlap in the LOW levels which would cause more than one output to be active at the same time. Parallel expansion to generate n-bit words is accomplished by driving the enable and address inputs of each device in parallel.

**WRITE MODE SELECT TABLE**

OPERATING MODE	INPUTS		INTERNAL LATCHES <sup>(b)</sup>
	$\overline{WE}$	$D_n$	
Write Data	L	L	L
	L	H	H
Data Latched	H	X	no change

NOTE  
b. The Write Address ( $W_A$  &  $W_B$ ) to the "internal latches" must be stable while  $\overline{WE}$  is LOW for conventional operation.

**READ MODE SELECT TABLE**

OPERATING MODE	$\overline{RE}$	INPUTS		OUTPUTS $Q_n$
		INTERNAL LATCHES <sup>(c)</sup>		
Read	L	L	L	L
	L	H	H	H
Disabled	H	X		(Z)

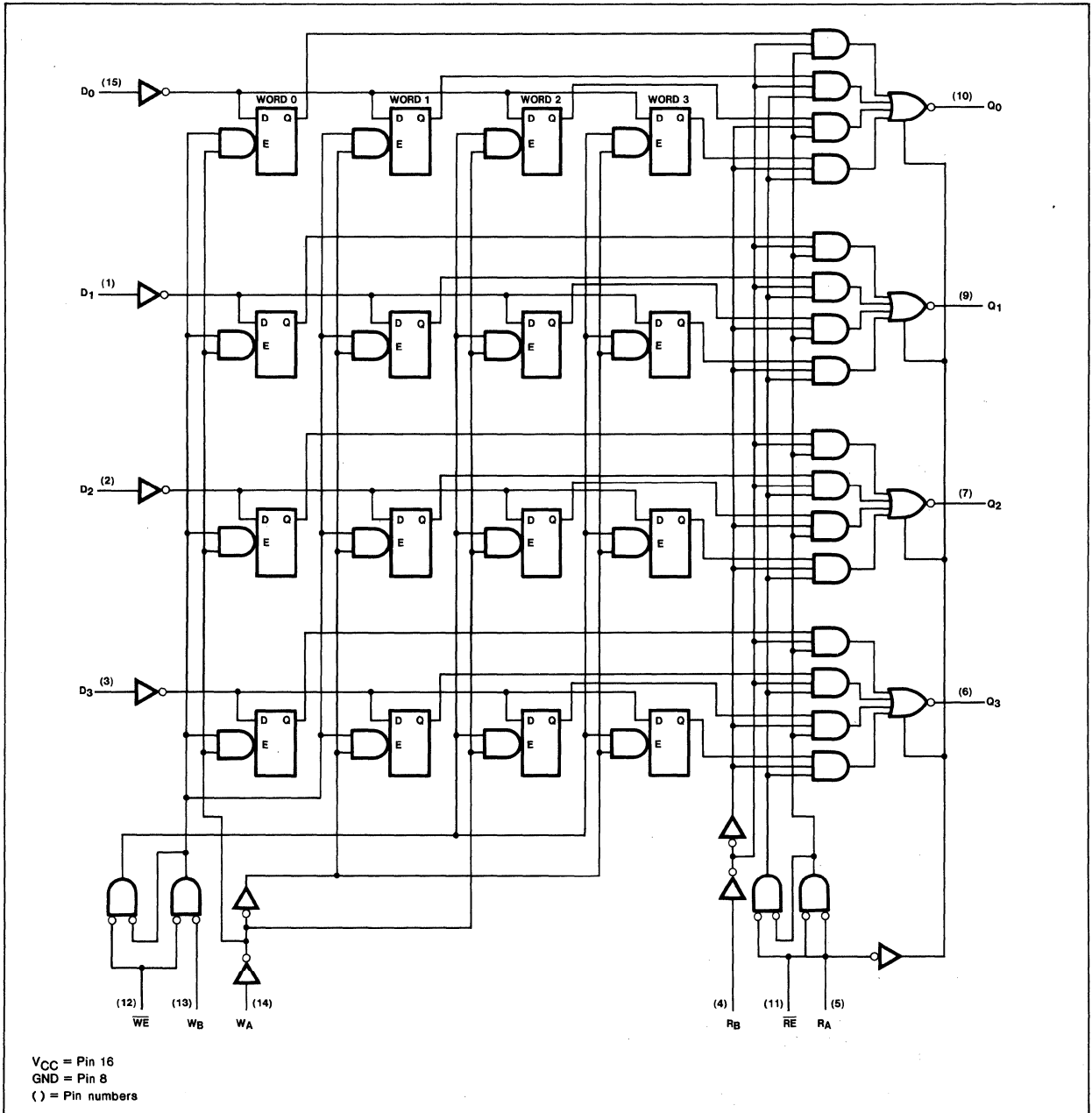
NOTE  
c. The Read Address ( $R_A$  &  $R_B$ ) changes to select the "internal latches" are not constrained by  $\overline{WE}$  or  $\overline{RE}$  operation.

H = HIGH voltage level  
L = LOW voltage level  
X = Don't care  
(Z) = High impedance "off" state

**AC CHARACTERISTICS:  $T_A=25^\circ\text{C}$  (See Section 4 for Test Circuits and Conditions)**

PARAMETER	TEST CONDITIONS	54/74		54S/74S		54LS/74LS		UNIT
						$C_L = 15\text{pF}$ $R_L = 2\text{k}\Omega$		
		Min	Max	Min	Max	Min	Max	
$t_{PLH}$	Propagation delay						40	ns
$t_{PHL}$	Read Address to output						45	ns
$t_{PLH}$	Propagation delay						45	ns
$t_{PHL}$	Write Enable to output						50	ns
$t_{PLH}$	Propagation delay						45	ns
$t_{PHL}$	Data to output						40	ns
$t_{PZH}$	Read enable time to HIGH level						35	ns
$t_{PZL}$	Read enable time to LOW level						40	ns
$t_{PHZ}$	Disable time from HIGH level						50	ns
$t_{PLZ}$	Disable time from LOW level						35	ns

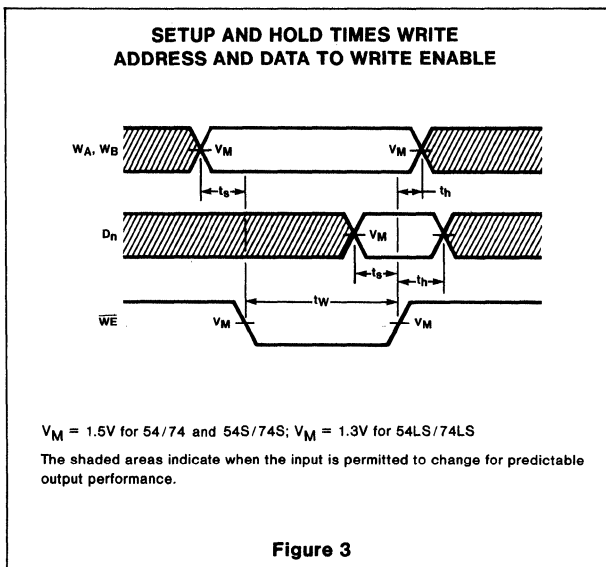
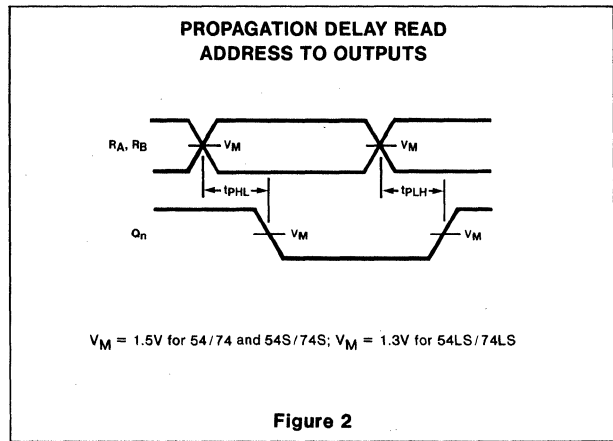
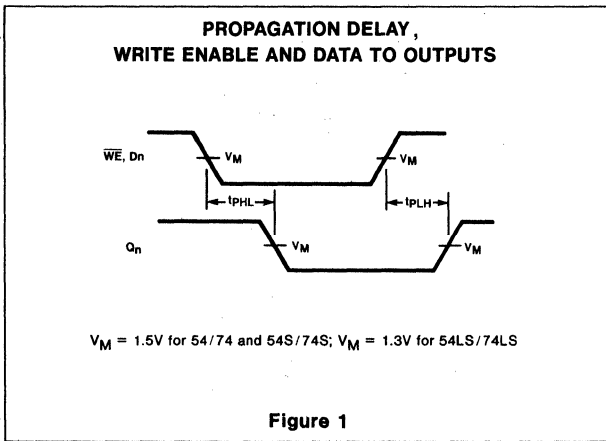
LOGIC DIAGRAM



AC SETUP REQUIREMENTS:  $T_A = 25^\circ\text{C}$  (See Section 4 for Test Circuits and Conditions)

PARAMETER	TEST CONDITIONS	54/74		54S/74S		54LS/74LS		UNIT
		Min	Max	Min	Max	Min	Max	
$t_W$	Write Enable pulse width					25		ns
$t_s$	Setup time Data to positive going $\overline{WE}$					10		ns
$t_h$	Hold time Data to positive going $\overline{WE}$					15		ns
$t_s$	Setup time Read Address to negative going $\overline{WE}$					15		ns
$t_h$	Hold time Read Address to positive going $\overline{WE}$					5.0		ns

AC WAVEFORMS



AC WAVEFORMS (Cont'd)

